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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC G2_LE
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	300MHz
Co-Processors/DSP	Communications; RISC CPM
RAM Controllers	DRAM, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100Mbps (2)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	516-BBGA
Supplier Device Package	516-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8247cvrpiea

1 Overview

This table shows the functionality supported by each SoC in the MPC8272 family.

Table 1. MPC8272 PowerQUICC II Family Functionality

Functionality	SoCs			
	MPC8272	MPC8248	MPC8271	MPC8247
Package[1]	516 PBGA			
Serial communications controllers (SCCs)	3	3	3	3
QUICC multi-channel controller (QMC)	Yes	Yes	Yes	Yes
Fast communication controllers (FCCs)	2	2	2	2
I-Cache (Kbyte)	16	16	16	16
D-Cache (Kbyte)	16	16	16	16
Ethernet (10/100)	2	2	2	2
UTOPIA II Ports	1	0	1	0
Multi-channel controllers (MCCs)	0	0	0	0
PCI bridge	Yes	Yes	Yes	Yes
Transmission convergence (TC) layer	—	—	—	—
Inverse multiplexing for ATM (IMA)	—	—	—	—
Universal serial bus (USB) 2.0 full/low rate	1	1	1	1
Security engine (SEC)	Yes	Yes	—	—

[1] See Table 2.

Devices in the MPC8272 family are available in two packages—the VR or ZQ package—as shown in . For package ordering information, see Section 10, “Ordering Information.”

Table 2. MPC8272 PowerQUICC II Device Packages

Code (Package)	VR (516 PBGA—Lead free)	ZQ (516 PBGA—Lead spheres)
Device	MPC8272VR	MPC8272ZQ
	MPC8248VR	MPC8248ZQ
	MPC8271VR	MPC8271ZQ
	MPC8247VR	MPC8247ZQ

This figure shows the block diagram of the SoC.

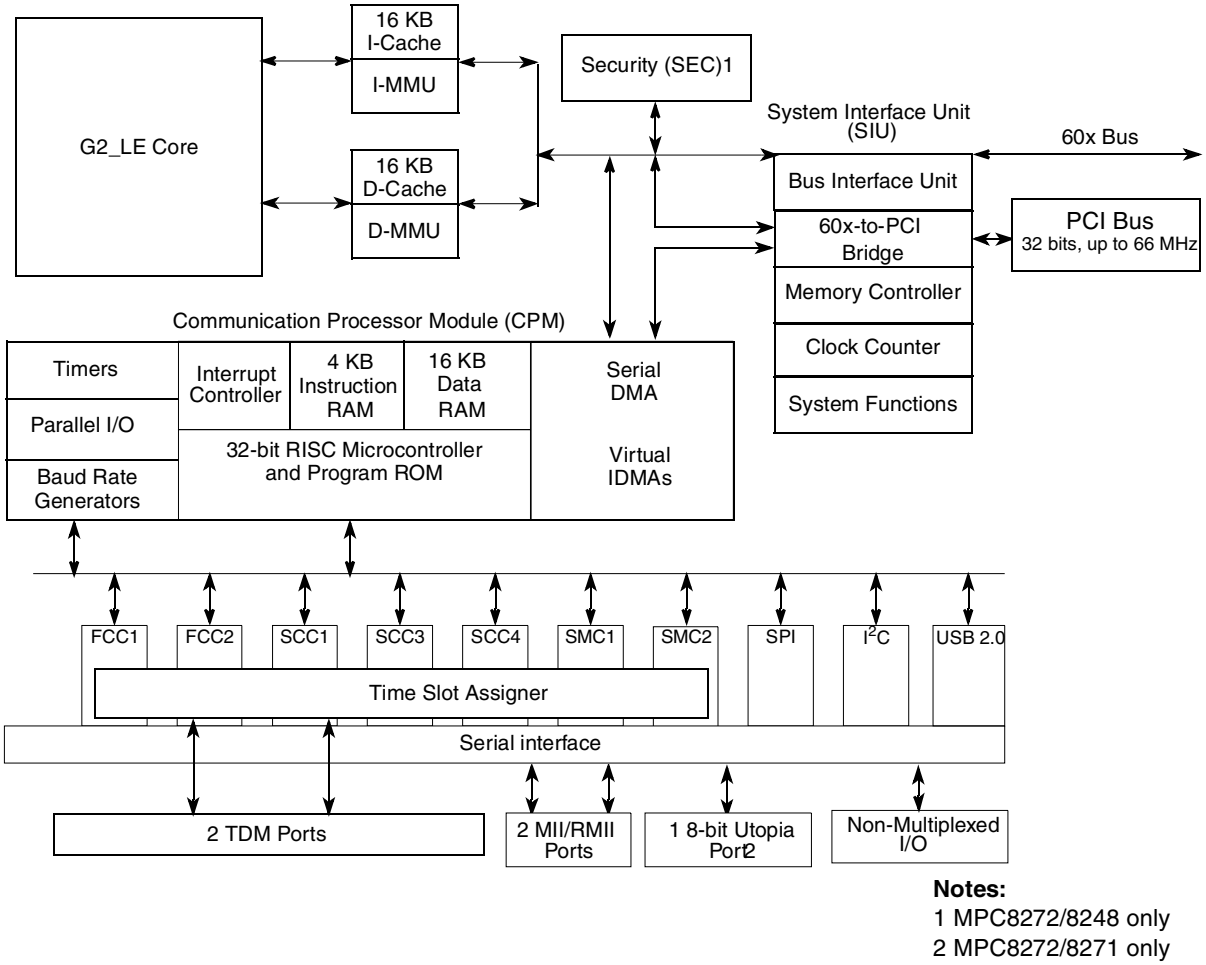

Figure 1. SoC Block Diagram

1.1 Features

The major features of the SoC are as follows:

- Dual-issue integer (G2_LE) core
  - A core version of the MPC603e microprocessor
  - System core microprocessor supporting frequencies of 266–400 MHz
  - Separate 16 KB data and instruction caches:
    - Four-way set associative
    - Physically addressed
    - LRU replacement algorithm
  - Power Architecture®-compliant memory management unit (MMU)
  - Common on-chip processor (COP) test interface
  - Supports bus snooping for cache coherency

- PCI bridge
  - PCI Specification revision 2.2-compliant and supports frequencies up to 66 MHz
  - On-chip arbitration
  - Support for PCI to 60x memory and 60x memory to PCI streaming
  - PCI host bridge or peripheral capabilities
  - Includes four DMA channels for the following transfers:
    - PCI-to-60x to 60x-to-PCI
    - 60x-to-PCI to PCI-to-60x
    - PCI-to-60x to PCI-to-60x
    - 60x-to-PCI to 60x-to-PCI
  - Includes the configuration registers required by the PCI standard (which are automatically loaded from the EPROM to configure the MPC8272) and message and doorbell registers
  - Supports the I_2O standard
  - Hot-Swap friendly (supports the Hot Swap Specification as defined by PICMG 2.1 R1.0 August 3, 1998)
  - Support for 66 MHz, 3.3 V specification
  - 60x-PCI bus core logic, which uses a buffer pool to allocate buffers for each port

2 Operating Conditions

This table shows the maximum electrical ratings.

Table 3. Absolute Maximum Ratings[1]

Rating	Symbol	Value	Unit
Core supply voltage[2]	VDD	–0.3 – 2.25	V
PLL supply voltage[2]	VCCSYN	–0.3 – 2.25	V
I/O supply voltage[3]	VDDH	–0.3 – 4.0	V
Input voltage[4]	VIN	GND(–0.3) – 3.6	V
Junction temperature	T_j	120	°C
Storage temperature range	T_{STG}	(–55) – (+150)	°C

1 Absolute maximum ratings are stress ratings only; functional operation (see Table 4) at the maximums is not guaranteed. Stress beyond those listed may affect device reliability or cause permanent damage.

2 **Caution:** VDD/VCCSYN must not exceed VDDH by more than 0.4 V during normal operation. It is recommended that VDD/VCCSYN should be raised before or simultaneous with VDDH during power-on reset. VDD/VCCSYN may exceed VDDH by more than 0.4 V during power-on reset for no more than 100 ms.

3 **Caution:** VDDH can exceed VDD/VCCSYN by 3.3 V during power on reset by no more than 100 mSec. VDDH should not exceed VDD/VCCSYN by more than 2.5 V during normal operation.

4 **Caution:** VIN must not exceed VDDH by more than 2.5 V at any time, including during power-on reset.

[5] MPC8272 and MPC8271 only.

Table 6.

Characteristic	Symbol	Min	Max	Unit
Input high voltage—all inputs except TCK, $\overline{TRST}$ and $\overline{PORESET}$[1]	V_{IH}	2.0	3.465	V
Input low voltage	V_{IL}	GND	0.8	V
CLKIN input high voltage	V_{IHC}	2.4	3.465	V
CLKIN input low voltage	V_{ILC}	GND	0.4	V
Input leakage current, V_{IN} = VDDH[2]	I_{IN}	—	10	μA
Hi-Z (off state) leakage current, V_{IN} = VDDH[2]	I_{OZ}	—	10	μA
Signal low input current, V_{IL} = 0.8 V[3]	I_L	—	1	μA
Signal high input current, V_{IH} = 2.0 V	I_H	—	1	μA
Output high voltage, I_{OH} = –2 mA except UTOPIA mode, and open drain pins In UTOPIA mode[4] (UTOPIA pins only): I_{OH} = -8.0mA	V_{OH}	2.4	—	V
In UTOPIA mode[4] (UTOPIA pins only): I_{OL} = 8.0mA	V_{OL}	—	0.5	V
I_{OL} = 6.0mA $\overline{BR}$ $\overline{BG}$ $\overline{ABB}$/$\overline{IRQ2}$ $\overline{TS}$ A[0-31] $\overline{TT}$[0-4] $\overline{TBST}$ TSIZE[0–3] $\overline{AACK}$ $\overline{ARTRY}$ $\overline{DBG}$ $\overline{DBB}$/$\overline{IRQ3}$ D[0-63] //$\overline{EXT_BR3}$ //$\overline{EXT_BG3}$ /$\overline{TBEN}$/$\overline{EXT_DBG3}$/$\overline{CINT}$ $\overline{PSDVAL}$ $\overline{TA}$ $\overline{TEA}$ $\overline{GBL}$/$\overline{IRQ1}$ $\overline{CI}$/BADDR29/$\overline{IRQ2}$ $\overline{WT}$/BADDR30/$\overline{IRQ3}$ BADDR31/$\overline{IRQ5}$/$\overline{CINT}$ $\overline{CPU_BR}$ $\overline{IRQ0}$/$\overline{NMI_OUT}$ /$\overline{PCI_RST}$ $\overline{HRESET}$ $\overline{SRESET}$ $\overline{RSTCONF}$	V_{OL}	—	0.4	V

Table 6.

Characteristic	Symbol	Min	Max	Unit
I_{OL} = 5.3mA CS[0-9] CS(10)/BCTL1 CS(11)/AP(0) BADDR[27–28] ALE BCTL0 PWE[0–7]/PSDDQM[0–7]/PBS[0–7] PSDA10/PGPL0 PSDWE/PGPL1 POE/PSDRAS/PGPL2 PSDCAS/PGPL3 PGTA/PUPMWAIT/PGPL4/PPBS PSDAMUX/PGPL5 LWE[0–3]LSDDQM[0–3]/LBS[0–3]/PCI_CFG[0–3] LSDA10/LGPL0/PCI_MODCKH0 LSDWE/LGPL1/PCI_MODCKH1 LOE/LSDRAS/LGPL2/PCI_MODCKH2 LSDCAS/LGPL3/PCI_MODCKH3 LGTA/LUPMWAIT/LGPL4/LPBS LSDAMUX/LGPL5/PCI_MODCK LWR MODCK[1–3]/AP[1–3]/TC[0–2]/BNKSEL[0–2]	V_{OL}	—	0.4	V
I_{OL} = 3.2mA L_A14/PAR L_A15/FRAME/SMI L_A16/TRDY L_A17/IRDY/CKSTP_OUT L_A18/STOP L_A19/DEVSEL L_A20/IDSEL L_A21/PERR L_A22/SERR L_A23/REQ0 L_A24/REQ1/HSEJSW L_A25/GNT0 L_A26/GNT1/HSLED L_A27/GNT2/HSENUM L_A28/RST/CORE_SRESET L_A29/INTAL_A30/REQ2 L_A31 LCL_D[0-31)]/AD[0-31] LCL_DP[03]/C/BE[0-3] PA[0–31] PB[4–31] PC[0–31] PD[4–31] TDO QREQ				

1 TCK, TRST and PORESET have min VIH = 2.5V.

2 The leakage current is measured for nominal VDDH,VCCSYN, and VDD.

3 V_{IL} for IIC interface does not match IIC standard, but does meet IIC standard for V_{OL} and should not cause any compatibility issue.

4.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (ºC/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the air flow around the device, add a heat sink, change the mounting arrangement on the printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

4.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature.

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

$R_{\theta JB}$ = junction-to-board thermal resistance (ºC/W)

T_B = board temperature (ºC)

P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and by attaching the thermal balls to the ground plane.

4.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application, or a more accurate and complex model of the package can be used in the thermal simulation.

4.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

Ψ_{JT} = thermal characterization parameter

T_T = thermocouple temperature on top of package

P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40-gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the case to avoid measurement errors caused by cooling effects of the thermocouple wire.

4.6 Layout Practices

Each VDD and VDDH pin should be provided with a low-impedance path to the board's power supplies. Each ground pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on chip. The VDD and VDDH power supplies should be bypassed to ground using bypass capacitors located as close as possible to the four sides of the package. For filtering high frequency noise, a capacitor of 0.1uF on each VDD and VDDH pin is recommended. Further, for medium frequency noise, a total of 2 capacitors of 47uF for VDD and 2 capacitors of 47uF for VDDH are also recommended. The capacitor leads and associated printed circuit traces connecting to chip VDD, VDDH and ground should be kept to less than half an inch per capacitor lead. Boards should employ separate inner layers for power and GND planes.

All output pins on the SoC have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized to minimize overdamped conditions and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of six inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the VDD and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.

This table lists CPM input characteristics.

NOTE: Rise/Fall Time on CPM Input Pins

It is recommended that the rise/fall time on CPM input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of VCC; fall time refers to transitions from 90% to 10% of VCC.

Table 11. AC Characteristics for CPM Inputs [1]

Spec Number		Characteristic	Value (ns)							
Setup	Hold		Setup				Hold			
			66 MHz	83 MHz	100 MHz	133 MHz	66 MHz	83 MHz	100 MHz	133 MHz
sp16a	sp17a	FCC inputs—internal clock (NMSI)	6	6	6	6	0	0	0	0
sp16b	sp17b	FCC inputs—external clock (NMSI)	2.5	2.5	2.5	2.5	2	2	2	2
sp18a	sp19a	SCC/SMC/SPI/I2C inputs—internal clock (NMSI)	6	6	6	6	0	0	0	0
sp18b	sp19b	SCC/SMC/SPI/I2C inputs—external clock (NMSI)	4	4	4	4	2	2	2	2
sp20	sp21	TDM inputs/SI	3	3	3	3	2.5	2.5	2.5	2.5
sp22	sp23	PIO/TIMER/IDMA inputs	8	8	8	8	0.5	0.5	0.5	0.5

[1] Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.

NOTE

Although the specifications generally reference the rising edge of the clock, the following AC timing diagrams also apply when the falling edge is the active edge.

This figure shows the FCC internal clock.

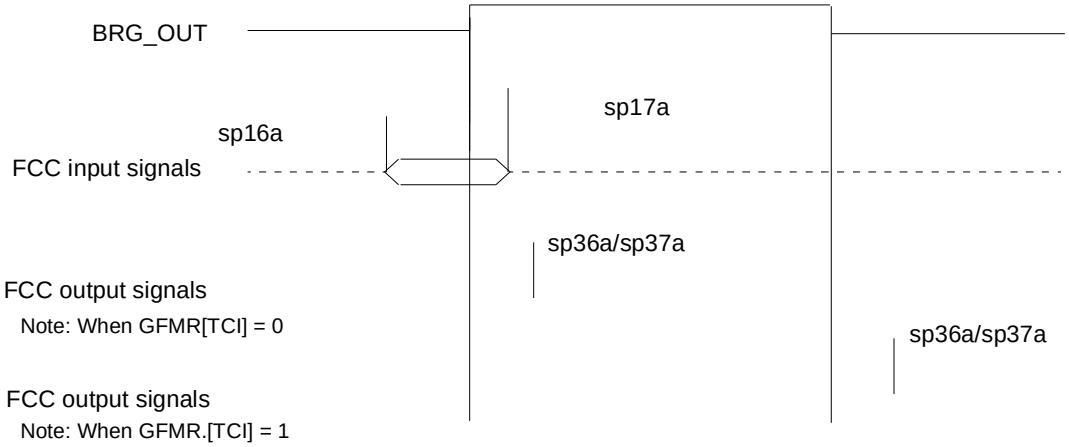

Figure 3. FCC Internal Clock Diagram

NOTE

The UPM machine outputs change on the internal tick determined by the memory controller programming; the AC specifications are relative to the internal tick. Note that SDRAM and GPCM machine outputs change on CLKin's rising edge.

6.3 JTAG Timings

This table lists the JTAG timings.

Table 15. JTAG Timings [1]

Parameter	Symbol [2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4V	t_{JTKHKL}	15	—	ns	—
JTAG external clock rise and fall times	t_{JTGR} and t_{JTGF}	0	5	ns	[6]
TRST assert time	t_{TRST}	25	—	ns	[3,6]
Input setup times Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 4	 — —	 ns ns	 [4,7] [4,7]
Input hold times Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 10 10	 — —	 ns ns	 [4,7] [4,7]
Output valid times Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 — —	 10 10	 ns ns	 [5,7] [5,7]
Output hold times Boundary-scan data TDO	 t_{JTKLDX} t_{JTKLOX}	 1 1	 — —	 ns ns	 [5,7] [5,7]
JTAG external clock to output high impedance Boundary-scan data TDO	 t_{JTKLDZ} t_{JTKLOZ}	 1 1	 10 10	 ns ns	 [5,6] [5,6]

1 All outputs are measured from the midpoint voltage of the falling/rising edge of t_{TCLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50- load. Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.

2 The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{((first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{JTDVKH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

3 TRST is an asynchronous level sensitive signal. The setup time is for test purposes only.

4 Non-JTAG signal input timing with respect to t_{TCLK}.

5 Non-JTAG signal output timing with respect to t_{TCLK}.

6 Guaranteed by design.

7 Guaranteed by design and device characterization.